1 4607 ((257/48) or (438/18) or (324/158.1) or (324/133) or (324/501)).CCLS. 2 1 (((257/48) or (438/18) or (324/158.1) or (324/133) or (324/501)).CCLS.) and (laser (324/133) or (324/501)).CCLS.) and (laser (324/133) or (324/501)).CCLS.) and (laser (324/133) or (324/501)).CCLS.) and (taser (324/133) or (324/501)).CCLS.) and (test (324/133)) or (324/501)).CCLS.) and (test (324/133)) or (324/501)).CCLS.) and (test (324/133)) or (324/133) or (324/501)).CCLS.) and (test (324/133)) or (324/133) or (324/138.1) or			·	CF	
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345   (((257/48) or (438/18) or (324/158.1) or (324/133) or (324/501)).CCLS.) and (test testing non-invasive laser adj voltage adj probe lvp) near6 gate					
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_	l o l	((257/48).CCLS.) and optical near3 prob\$3	USPAT;	2003/03/03 17:16
.		near6 gate and (cmos or cmosfet) and	US-PGPUB;	2003/03/03 17:16
		(laser or irradiat\$3)	EPO; JPO;	
		(###OCT OI III##I##CYJ)		l
			DERWENT;	İ
	<u> </u>		IBM_TDB	

-	0	( (20 ) to ( to 20 ) to and of order mounts from the	USPAT;	2003/03/03 17:17
		near6 gate and (cmos or cmosfet)	US-PGPUB;	
			EPO; JPO;	
			DERWENT;	
1.		(4057/40) 6070 ) (1)	IBM_TDB	0000/00/00 17 10
-	0	((20:, 10, 100201, 2002 02 20020010 02	USPAT;	2003/03/03 17:18
		irradiat\$3) near6 prob\$3 near6 gate	US-PGPUB;	
· ·			EPO; JPO;	
			DERWENT;	
	33	((257/48).CCLS.) and prob\$3 near6 gate	IBM_TDB USPAT;	2003/03/03 17:19
-	33	((257/48).CCLS.) and prob\$3 hears gate	US-PGPUB;	2003/03/03 17:19
			EPO; JPO;	
			DERWENT;	
			IBM TDB	
_	31	(((257/48).CCLS.) and prob\$3 near6 gate)	USPAT;	2003/03/03 17:20
		not (((257/48).CCLS.) and test\$3 near6	US-PGPUB;	2003/03/03 17.20
		gate and (cmos or cmosfet))	EPO; JPO;	
		gada ana (amas az amaszad),	DERWENT;	
			IBM TDB	
-	24	((257/48).CCLS.) and laser near6 (test\$3	USPAT;	2003/03/03 17:21
	I	or prob\$3)	US-PGPUB;	
1			EPO; JPO;	
			DERWENT;	]
			IBM_TDB	
-	38	((257/48).CCLS.) and (optical or laser)	USPAT;	2003/03/03 17:26
		near6 (test\$3 or prob\$3)	US-PGPUB;	
	[.		EPO; JPO;	1
			DERWENT;	
		(1057/10) 0070	IBM_TDB	
-	1	((257/48).CCLS.) and (lvp or laser adj	USPAT;	2003/03/03 17:27
		voltage adj probe)	US-PGPUB;	
			EPO; JPO;	
			DERWENT;	
1_	33	/lum or lagor add woltage add make) and	IBM_TDB	2002/02/02 17:20
	33	(lvp or laser adj voltage adj probe) and (mos or cmos or mosfet or cmosfet)	USPAT; US-PGPUB;	2003/03/03 17:28
	İ	(mos of chos of moster of choster)	EPO; JPO;	
			DERWENT;	
			IBM TDB	
-	3	(lvp or laser adj voltage adj probe) and	USPĀT;	2003/03/03 17:29
		(mos or cmos or mosfet or cmosfet) and	US-PGPUB;	
		(test\$3 or prob\$3) near6 gate	EPO; JPO;	
		-	DERWENT;	
]			IBM TDB	<u> </u>
-	44	(lvp or laser adj voltage adj	USPAT;	2003/03/03 20:39
		probing).ti,ab,clm.	US-PGPUB;	
			EPO; JPO;	,
			DERWENT;	
		Though adds on besteride as to the state of the	IBM_TDB	0000 (00 (0)
-	0	(back-side or backside or back adj side)	USPAT;	2003/03/04 09:54
		near3 (lvp or laser adj voltage adj	US-PGPUB;	
		(probing or probe))	EPO; JPO;	
į.			DERWENT;	.
_	1	(back-side or backside or back adj side)	<pre>IBM_TDB USPAT;</pre>	2003/03/04 10:05
	*	near12 (lvp or laser adj voltage adj	US-PGPUB;	2003/03/04 10:03
		(probing or probe))	EPO; JPO;	
		(1	DERWENT;	
			IBM TDB	
-	1	"6428718".PN.	USPAT	2003/03/04 09:57
-	1	"6403439".PN.	USPAT	2003/03/04 10:03
-	10	(lvp or laser adj voltage adj (probing or	USPAT;	2003/03/04 10:59
1		probe)) and (cmos or cmosfet)	US-PGPUB;	
			EPO; JPO;	
			DERWENT;	
_			IBM_TDB	
	1	"6331453".PN.	USPAT	2003/03/04 10:09

_	1	non-invasive near3 optical near12 (cmos or	USPAT;	2003/03/04 10:15
		cmosfet)	US-PGPUB;	
İ			EPO; JPO;	
			DERWENT;	
1_	13	reverse adj voltage near6 (cmos or	IBM_TDB USPAT;	2003/03/04 11:01
		cmosfet)	US-PGPUB;	2003/03/04 11:01
		Chiosice	EPO; JPO;	
			DERWENT;	
			IBM TDB	
-	1	reverse adj voltage near6 (cmos or	USPAT;	2003/03/04 11:02
		cmosfet) and (laser adj voltage adj	US-PGPUB;	
		(probing or probe))	EPO; JPO;	
			DERWENT;	
	11	reverse adj voltage near6 (cmos or	IBM_TDB	2003 (03 (04 11 06
_	1	cmosfet) and (test\$3 or prob\$3)	USPAT; US-PGPUB;	2003/03/04 11:06
		chostet/ and (test) of plobs(3)	EPO; JPO;	
			DERWENT;	
			IBM TDB	
-	2	reverse adj voltage near6 (cmos or	USPĀT;	2003/03/04 12:00
		cmosfet) and (test\$3 or probe or probing)	US-PGPUB;	
			EPO; JPO;	
	'		DERWENT;	1
	2	(11,000,40,0711) 702	IBM_TDB	
-		("6084267").PN.	USPAT;	2003/03/04 12:00
	1		US-PGPUB; EPO; JPO;	
			DERWENT;	
			IBM TDB	
-	11	(((257/48).CCLS.) or 324/158.\$3.ccls.) and	USPAT;	2003/08/05 10:57
	1	(mosfet or cmosfet or nmosfet or pmosfet	US-PGPUB;	
	1	or cmos or nmos or pmos) and (test or	EPO; JPO;	
		testing or diagnostic) near12 laser	DERWENT;	
1	,	(#C107100#) PV	IBM_TDB	
<del>-</del>	3018	1 , , , , , , , , , , , , , , ,	USPAT	2003/08/05 15:37
-	3016	324/158\$3.ccls. 257/48.ccls. 438/18.ccls.	USPAT; US-PGPUB	2003/08/05 19:09
_	77	(324/158\$3.ccls. 257/48.ccls.	USPAT;	2003/08/05 19:12
	'	438/18.ccls.) and (lvp laser adj voltage	US-PGPUB;	2003/08/03 19:12
		adj probe laser-voltage-probe laser adj	EPO; JPO;	
}		voltage-probe (laser near12 (test\$3	DERWENT;	
		diagnostic\$1)))	IBM_TDB	
_	100	yoshida.in. and eiji.in.	USPAT;	2003/08/06 08:42
_	1	workids in and sidi in and	US-PGPUB	0000/00/06 00 10
_	1	yoshida.in. and eiji.in. and transistor.clm. and laser.clm.	USPAT; US-PGPUB	2003/08/06 08:43
_	6	yoshida.in. and eiji.in. and semiconductor	USPAT;	2003/10/19 15:14
		and gate and laser	US-PGPUB;	2003/10/13 13:14
			EPO; JPO;	.
		•	DERWENT;	
		/#.C10000000	IBM_TDB	
_	2	("6137295").PN.	USPAT;	2003/10/19 15:15
			US-PGPUB;	
		·	EPO; JPO;	
			DERWENT; IBM TDB	[
_	6	392925.ap.	USPAT;	2003/10/19 15:27
		•	US-PGPUB;	
•	]		EPO; JPO;	
			DERWENT;	
	[	//204/150 1)	IBM_TDB	
-	5806	(	USPAT;	2003/10/19 15:27
		(257/48)).CCLS.	US-PGPUB;	
			EPO; JPO; DERWENT;	
	ļ	•	IBM TDB	
-	10	(((324/158.1) or (324/501) or	USPAT;	2003/10/19 15:41
		(257/48)).CCLS.) and laser near20 junction	US-PGPUB;	1000,10,15 15.41
		,	EPO; JPO;	
			DERWENT;	
	L		IBM_TDB	

	,			
-	398	(438/18).CCLS.	USPAT;	2003/10/19 15:41
			US-PGPUB;	
1		,	EPO; JPO;	
	1		DERWENT;	İ
			IBM TDB	
-	2	((438/18).CCLS.) and laser near20 junction	USPAT;	2003/10/19 15:41
	ł		US-PGPUB;	
	1	· ·	EPO; JPO;	
			DERWENT;	
			IBM TDB	
1 -	1 6	lvp.ti,ab,clm. and probe	USPAT;	2003/10/19 15:56
			US-PGPUB;	] = 000, = 0, = 0
			EPO; JPO;	
1			DERWENT;	
1	1		IBM TDB	
_	437	cmos.ti,ab,clm. and drain near3 (connect	USPAT	2003/10/19 18:18
	457	connected) near3 source and common near2	USFAI	2003/10/19 18:16
1		(source drain)		·
1_	109		HODAM	2002/10/10 10 10
1	109		USPAT	2003/10/19 18:19
}		connected) near3 source and common near2		
		(source drain) and 257/\$9.ccls.	l	
_	299		USPAT;	2003/10/19 19:45
	_	drain) and 257/\$9.ccls.	EPO; JPO	
-	0	dillinger.in. and protection and gate	USPAT;	2003/10/19 19:48
			EPO; JPO;	
		·	DERWENT	l
-	74		USPAT;	2003/10/19 19:53
		438/\$9.ccls.)	EPO; JPO;	!
			DERWENT	li
-	9	(latchup latch-up) near12 testing and	USPAT;	2003/10/19 20:10
		(257/\$9.ccls. 438/\$9.ccls.)	EPO; JPO;	
	İ		DERWENT	
-	1012	(257/48).CCLS.	USPAT;	2003/10/19 20:11
			US-PGPUB;	
		•	EPO; JPO;	1
			DERWENT;	
			IBM TDB	1
-	1012	(257/48).CCLS.	USPAT;	2003/10/19 20:11
[		•	US-PGPUB;	
			EPO; JPO;	[
			DERWENT;	1
}			IBM TDB	
_	542	(257/48).CCLS.	USPAT	2003/10/19 20:13
_	27	((257/48).CCLS.) and pmos and nmos	USPAT;	2003/10/19 20:13
	[ ~ '	(120.7.107.100HD17 and philos and inhos	US-PGPUB;	2003/10/19 20:13
]				
		· ·	EPO; JPO;	
			DERWENT;	
<u> </u>	3	931104 25	IBM_TDB	0004410410 17 55
	3	931104.ap.	USPAT;	2004/10/13 17:00
			US-PGPUB;	İ
.			EPO; JPO;	
			DERWENT;	
			IBM_TDB	